

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	35	("local probe storage array" OR "probe storage" OR "probe storage array").clm.	US-PGPUB	OR	OFF	2006/02/20 15:23
S1	15	local NEAR3 probe NEAR3 storage NEAR3 array	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 10:49
S2	2	("20040019757").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 15:05
S3	13	local NEAR2 probe NEAR2 storage NEAR2 array	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 15:20
S4	4	local NEAR1 probe NEAR1 storage NEAR1 array	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 10:50
S6	4749645	(INTERNATIONAL BUSINESS MACHINES CORP\$.as.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 11:43
S7	553	(711/104).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 11:55
S8	13	local NEAR2 probe NEAR2 storage NEAR2 array	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 15:21
S9	28	(local NEAR2 probe NEAR2 storage NEAR2 array) OR (local NEAR2 probe NEAR2 array)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 15:22
S10	26896	"711"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:36
S11	661916	367/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 08:56

S12	2759	S10 AND S11	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 08:56
S14	686053	S10 OR S11	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 09:04
S15	28	(local NEAR2 probe NEAR2 storage NEAR2 array) OR (local NEAR2 probe NEAR2 array)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 09:04
S16	13	S14 AND S15	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 15:06
S18	51	"processing elements" NEAR4 (sensor OR probe)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:37
S19	0	S12 AND S18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:37
S20	0	S14 AND S18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:37
S21	185	"processing elements" WITH (sensor OR probe)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:39
S22	5	S21 AND S14	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:40
S23	1	("5307311").PN.	USPAT; USOCR	OR	OFF	2005/09/26 15:06
S24	563761	"data processing element" NEAR "5" ("RAM" OR "random access memory")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 15:06

S25	21	"data processing element" NEAR5 ("RAM" OR "random access memory")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:12
S26	81	dedicated WITH ("user data" AND ("program code" OR "code"))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:14
S27	21	dedicated WITH ("user data" NEAR5("program code" OR "code"))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/28 08:48
S28	3156	"storage surface"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:15
S29	2	S28 AND S26	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:16
S30	143	"storage surface" WITH ("user data" AND ("program code" OR "code"))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:20
S31	2	dedicated WITH ("storage surface" WITH ("user data" AND ("program code" OR "code")))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:21
S32	707	((711/4) or (711/123)).CCLS.	USPAT; USOCR	OR	OFF	2005/09/28 09:27
S33	3156	"storage surface"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/28 08:49
S34	10	S32 AND S33	US-PGPUB; USPAT	OR	OFF	2005/09/28 08:53
S35	8	S32 AND "processing elements"	US-PGPUB; USPAT	OR	OFF	2005/09/28 08:53
S36	1902	((711/4) or (711/123) or (711/129) or (711/173)).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/28 09:28

S37	20	S36 AND S33	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/28 09:29
S38	4892	"storage array"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/18 13:01
S39	3259	"storage surface"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/18 13:01
S40	31	S38 AND S39	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/18 13:01


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Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, II CNF = IEE Conference, IEEE STD = IEEE Standard

1. **Signal processing for probe storage**  
 Pozidis, H.; Bachtold, P.; Cherubini, G.; Eleftheriou, E.; Hagleitner, C.; Pantazi, A.; Sebastian, A.;  
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2. **Servo and tracking algorithm for a probe storage system**  
 Dong-Ki Min; Seungbum Hong;  
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3. **Two-sensor-based H<sub>∞</sub> control for nanopositioning in probe storage**  
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5. **Analytical and micromagnetic-based modeling of quantization noise in MFM-based pulse-width-Modulation perpendicular recording**  
 El-Sayed, R.T.; Carley, L.R.;  
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6. **The race to the bottom [consumer nanodevice]**  
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7. **Fabrication of patterned Pt/Co multilayers for high-density probe storage**  
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10. **Terabit-per-square-inch data storage using phase-change media and scanning electrical nanoprobe**  
Wright, C.D.; Armand, M.; Aziz, M.M.;  
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11. **Performance analysis of a 0.3-Tb/in/sup 2/ low-power MFM-based scanning-probe device**  
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12. **Demonstration of thermomechanical recording at 641 Gbit/in/sup 2/**  
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15. **Thousands of microcantilevers for highly parallel and ultra-dense data storage**  
Vettiger, P.; Albrecht, T.; Despont, M.; Drechsler, U.; Durig, U.; Gotsmann, B.; Jubin, D.; Haberle, W.; Lantz, M.A.; Rothuizen, H.; Stutz, R.; Wiesmann, D.; Binnig, G.K.; Bachtold, P.; Cherubini, G.; Hagleitner, C.; Loeliger, T.; Panta, A.; Pozidis, H.; Eleftheriou, E.;  
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Key: IEEE JNL = IEEE Journal or Magazine, IEEE JNL = IEEE Journal or Magazine, IEEE CNF = IEEE Conference, IEEE CNF = IEEE Conference, IEEE STD = IEEE Standard

1. **Design of atomic force microscope cantilevers for combined thermomechanical writing and thermal reading in array operation**  
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2. **The "millipede" - nanotechnology entering data storage**  
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4. **A beautiful noise [invention of STM and AFM]**  
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5. **CMOS sensor array with cell-level analog-to-digital conversion for local probe data storage**  
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16. **Scanning probe microscopy-how does it work and what might you use it for?**



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